



2015 International Symposium on Dependable Integrated Systems

March 16, 2015

Graduate Seminar Room 7F, General Research Building, Kyutech Iizuka Campus Dependable Integrated Systems Research Center, Kyushu Institute of Technology

■09:30~09:40 Opening & Introduction to DISC

Xiaoqing Wen, Professor and Director of DISC, Kyutech, Japan

■09:40~10:15 Invited Talk 1

• On Generating Compact Test Sets Sudhakar M. Reddy, Professor, University of Iowa, USA

■10:15~10:50 Invited Talk 2

• High Test Quality and Low Test Costs - Two Challenging Facets of Manufacturing Test
Nilanjan Mukherjee, Engineering Director, Test Synthesis, Silicon Test Solution, Mentor Graphics, USA

■10:50~11:00 Break

■11:00~11:35 Invited Talk 3

• GPU-Based Fault Simulation and Test Generation

James Chien-Mo Li, Professor, National Taiwan University, Taiwan

■11:35~12:10 Invited Talk 4

· Dependable Traffic Control System in Vietnam

Bui Huu Phu, Professor and Vice Director, Institute of Applied Mechanics and Informatics, Vietnam Academic of Science and Technology, Vietnam

■12:10~13:20 Lunch

■13:20~13:55 Invited Talk 5

· IC Testing Industry - Past, Today, and Future

Manabu Kimura, CEO, Cloud Testing Service, Inc., Japan

■13:55~15:10 DISC Research Presentation I (LSI Design)

Chair: Kohei Miyase, Assistant Professor, DISC, Kyutech, Japan

- 1. Hardware-Software Coverification for Complex SoC System Using Synopsys HAPS Platform Nana Sutisna, Leonardo Lanante Jr., Yuhei Nagao, Masayuki Kurosaki, and Hiroshi Ochi
- 2. Model-based Design Method for Wireless LAN VLSI System with Synopsys Synphony Tool Yuji Yokota, Thi Hong Tran, Yuhei Nagao, Masayuki Kurosaki, Hiroshi Ochi, and Baiko SAI
- 3. An Optimal Design Method for CMOS Even-Stage Ring Oscillators Containing Latches
 Yusuke Kohara, Tomohiro Fukuda, Kohei Ota, Yutaka Hirakawa, Masaharu Asano, Yoshihiro Kawakami, Yasuhisa Uchida,
 Hiroki Koike, and Kazuyuki Nakamura

■15:10~15:20 Break

■15:20~16:35 DISC Research Presentation II (LSI Test)

Chair: Leonardo Lanante, Assistant Professor, DISC, Kyutech, Japan

- 4. A Ratio-less Full-complementary 12-transistor SRAM for Ultra-low Supply-voltage Operation
 Takahiro Kondo, Hiromasa Yamamoto, Satoko Hoketsu, Hitoshi Imi, Hitoshi Okamura, Kazuyuki Nakamura
- 5. A TPG to Generate Pseudo Random Patterns with an Arbitrary Toggle Tate for Scan BIST Takaaki Kato, Senling Wang, Yasuo Sato, and Seiji Kajihara
- 6. Techniques for Mitigating Soft Errors in TCAMs

Infall Syafalni, Tsutomu Sasao, Xiaoqing Wen, and Stefan Holst

■16:35~16:40 Closing

Xiaoqing Wen, Professor and Director of DISC, Kyutech, Japan